



## 7<sup>th</sup> IEEE Electron Devices Technology and Manufacturing (EDTM) Conference 2023

March 7 – 10, 2023 / COEX Seoul, Korea

### 20F. RRAM and PCM

<b>Session Date:</b>	March 8(Wed.), 2023
<b>Session Time:</b>	15:15-16:40
<b>Session Room:</b>	Room F (#317)
<b>Session Chair:</b>	Dr. Gabriele Navarro (CEA-LETI)

[20F-1] [Invited]

15:15-15:40

#### Device-Algorithm Co-optimization for Neuromorphic Computing

Sangbum Kim

*Seoul National University*

[20F-2]

15:40-15:55

#### Analysis of Valence Change Mechanism Memristors Considering Charge Transition of Oxygen Vacancies

Juseong Park and Kyung Min Kim

*Korea Advanced Institute of Science and Technology*

[20F-3]

15:55-16:10

#### Controllable Conductive Filament Formation in Resistive-RAM Using ZnO Nanoparticles and Its Mechanisms

Jun-Ho Byun, Woon-San Ko, Ki-Nam Kim, Do-Yeon Lee, Eun-Gi Kim, Eun-A Koo, So-Yeon Kwon and Ga-Won Lee

*Chungnam National University*

[20F-4]

16:10-16:25

#### Crossbar Arrays Based on “Wall” Phase-Change Memory (PCM) and Ovonic-Threshold Switching (OTS) Selector: a Device Integration Challenge Towards New Computing Paradigms in Embedded Applications

G. Bourgeois, V. Meli, R. Antonelli, C. Socquet-Clerc, T. Magis, F. Laulagnet, B. Hemard, M. Bernard, L. Fellouh, P. Dezest, J. Krawczyk, S. Dominguez, F. Baudin, J. Garrione, C. Pellissier, J.-A. Dallery, N. Castellani, M.-C. Cyrille, C. Charpin, F. Andrieu and G. Navarro

*Université Grenoble Alpes CEA-Leti*

[20F-5]

16:25-16:40

#### Five-Fold Reduction in RESET Energy Consumption by Nitrogen Doping in Phase Change Memory

Wasi Uddin<sup>1</sup>, Ajay Kumar Agrawal<sup>1</sup>, Paritosh Meihar<sup>1</sup>, Avinash Singh<sup>2</sup>, Tarun Malviya<sup>2</sup>, Rohit Ranjan<sup>2</sup>, Sandip Lashkare<sup>1</sup>, Kumar Priyadarshi<sup>1</sup> and Udayan Ganguly<sup>1</sup>

<sup>1</sup>*Indian Institute of Technology Bombay*, <sup>2</sup>*Semi-Conductor Laboratory*